Quad D Flip-Flop

The LSTTL/MSI SN74LS175 is a high speed Quad D Flip-Flop. The device is useful for general flip-flop requirements where clock and clear inputs are common. The information on the D inputs is stored during the LOW to HIGH clock transition. Both true and complemented outputs of each flip-flop are provided. A Master Reset input resets all flip-flops, independent of the Clock or D inputs, when LOW.

The LS175 is fabricated with the Schottky barrier diode process for high speed and is completely compatible with all ON Semiconductor TTL families.

- Edge-Triggered D-Type Inputs
- Buffered-Positive Edge-Triggered Clock
- Clock to Output Delays of 30 ns
- Asynchronous Common Reset
- True and Complement Output
- Input Clamp Diodes Limit High Speed Termination Effects

GUARANTEED OPERATING RANGES

Symbol	Parameter	Min	Тур	Max	Unit
V _{CC}	Supply Voltage	4.75	5.0	5.25	V
T _A	Operating Ambient Temperature Range		25	70	°C
I _{OH}	I _{OH} Output Current – High			-0.4	mA
I _{OL} Output Current – Low				8.0	mA



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LOW POWER SCHOTTKY



N SUFFIX CASE 648



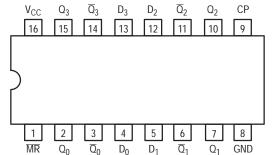
SOIC D SUFFIX CASE 751B

ORDERING INFORMATION

Device	Package	Shipping		
SN74LS175N	16 Pin DIP	2000 Units/Box		
SN74LS175D	16 Pin	2500/Tape & Reel		

1

CONNECTION DIAGRAM DIP (TOP VIEW)

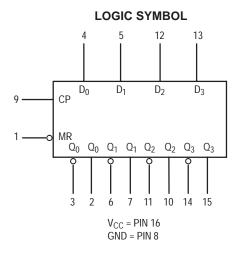


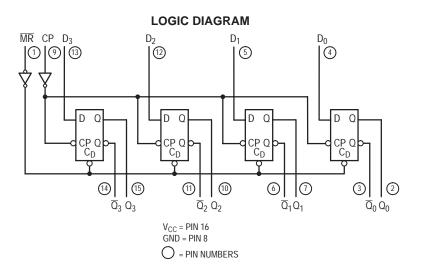
NOTE: The Flatpak version has the same pinouts (Connection Diagram) as the Dual In-Line Package.

		LOADING (Note a)	
PIN NAMES		HIGH	LOW
$D_0 - D_3$ CP \overline{MR} $Q_0 - Q_3$ $\overline{Q}_0 - \overline{Q}_3$	Data Inputs Clock (Active HIGH Going Edge) Input Master Reset (Active LOW) Input True Outputs Complemented Outputs	0.5 U.L. 0.5 U.L. 0.5 U.L. 10 U.L. 10 U.L.	0.25 U.L. 0.25 U.L. 0.25 U.L. 5 U.L. 5 U.L.

NOTES:

a) 1 TTL Unit Load (U.L.) = 40 μ A HIGH/1.6 mA LOW.





FUNCTIONAL DESCRIPTION

The LS175 consists of four edge-triggered D flip-flops with individual D inputs and Q and \overline{Q} outputs. The Clock and Master Reset are common. The four flip-flops will store the state of their individual D inputs on the LOW to HIGH Clock (CP) transition, causing individual Q and \overline{Q} outputs to

follow. A LOW input on the Master Reset (\overline{MR}) will force all Q outputs LOW and \overline{Q} outputs HIGH independent of Clock or Data inputs.

The LS175 is useful for general logic applications where a common Master Reset and Clock are acceptable.

TRUTH TABLE

Inputs (t = n, MR = H)	Outputs (t = n+1) Note 1			
D	Q	Q		
L	L	Н		
Н	Н	L		

Note 1: t = n + 1 indicates conditions after next clock.

DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE (unless otherwise specified)

		Limits						
Symbol	Parameter	Min	Тур	Max	Unit	Tes	Test Conditions	
V _{IH}	Input HIGH Voltage	2.0			V	Guaranteed Input HIGH Voltage for All Inputs		
V _{IL}	Input LOW Voltage			0.8	V	Guaranteed Input LOW Voltage for All Inputs		
V _{IK}	Input Clamp Diode Voltage		-0.65	-1.5	V	$V_{CC} = MIN, I_{IN} = -18 \text{ mA}$		
V _{OH}	Output HIGH Voltage	2.7	3.5		V	V_{CC} = MIN, I_{OH} = MAX, V_{IN} = V_{IH} or V_{IL} per Truth Table		
V	Output LOW/ Valtage		0.25	0.4	V	I _{OL} = 4.0 mA	$V_{CC} = V_{CC} MIN,$	
V _{OL}	Output LOW Voltage			0.5	V	I _{OL} = 8.0 mA	V _{IN} = V _{IL} or V _{IH} per Truth Table	
	Innut HICH Current			20	μΑ	V _{CC} = MAX, V _{IN} = 2.7 V		
l I _{IH}	Input HIGH Current			0.1	mA	V _{CC} = MAX, V _{IN} = 7.0 V		
I _{IL}	Input LOW Current			-0.4	mA	V _{CC} = MAX, V _{IN} = 0.4 V		
I _{OS}	Short Circuit Current (Note 1)	-20		-100	mA	V _{CC} = MAX		
I _{CC}	Power Supply Current			18	mA	V _{CC} = MAX		

Note 1: Not more than one output should be shorted at a time, nor for more than 1 second.

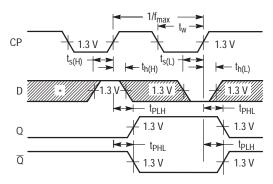
AC CHARACTERISTICS (T_A = 25°C)

		Limits				
Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions
f _{MAX}	Maximum Input Clock Frequency	30	40		MHz	
t _{PLH} t _{PHL}	Propagation Delay, MR to Output		20 20	30 30	ns	V _{CC} = 5.0 V C _I = 15 pF
t _{PLH} t _{PHL}	Propagation Delay, Clock to Output		13 16	25 25	ns	

AC SETUP REQUIREMENTS $(T_A = 25^{\circ}C)$

		Limits					
Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	
t _W	Clock or MR Pulse Width	20			ns		
t _s	Data Setup Time	20			ns	V 50V	
t _h	Data Hold Time	5.0			ns	$V_{CC} = 5.0 \text{ V}$	
t _{rec}	Recovery Time	25			ns		

AC WAVEFORMS



^{*}The shaded areas indicate when the input is permitted to change for predictable output performance.

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Figure 2. Master Reset to Output Delay, Master Reset Pulse Width, and Master Reset Recovery Time

Figure 1. Clock to Output Delays, Clock Pulse Width, Frequency, Setup and Hold Times Data to Clock

DEFINITIONS OF TERMS

SETUP TIME (t_s) — is defined as the minimum time required for the correct logic level to be present at the logic input prior to the clock transition from LOW to HIGH in order to be recognized and transferred to the outputs.

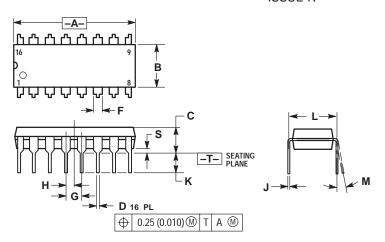
HOLD TIME (t_h) — is defined as the minimum time following the clock transition from LOW to HIGH that the logic level must be maintained at the input in order to ensure

continued recognition. A negative HOLD TIME indicates that the correct logic level may be released prior to the clock transition from LOW to HIGH and still be recognized.

RECOVERY TIME (t_{rec})—is defined as the minimum time required between the end of the reset pulse and the clock transition from LOW to HIGH in order to recognize and transfer HIGH Data to the Q outputs.

PACKAGE DIMENSIONS

N SUFFIX PLASTIC PACKAGE CASE 648-08 ISSUE R

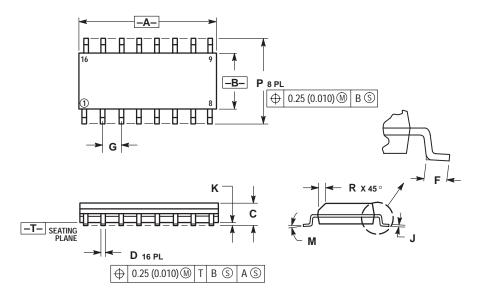


- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.
 3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
 4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
 5. ROUNDED CORNERS OPTIONAL.

	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.740	0.770	18.80	19.55	
В	0.250	0.270	6.35	6.85	
С	0.145	0.175	3.69	4.44	
D	0.015	0.021	0.39	0.53	
F	0.040	0.70	1.02	1.77	
G	0.100	BSC	2.54 BSC		
Н	0.050	BSC	1.27 BSC		
J	0.008	0.015	0.21	0.38	
K	0.110	0.130	2.80	3.30	
L	0.295	0.305	7.50	7.74	
М	0°	10 °	0°	10 °	
S	0.020	0.040	0.51	1.01	

PACKAGE DIMENSIONS

D SUFFIX PLASTIC SOIC PACKAGE CASE 751B-05 **ISSUE J**



NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER.

 3. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.

 4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.

 5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

· · · · · · · · · · · · · · · · · · ·									
	MILLIN	IETERS	INCHES						
DIM	MIN	MIN MAX MIN		MAX					
Α	9.80	10.00	0.386	0.393					
В	3.80	4.00	0.150	0.157					
С	1.35	1.75	0.054	0.068					
D	0.35	0.49	0.014	0.019					
F	0.40	1.25	0.016	0.049					
G	1.27	BSC	0.050	BSC					
J	0.19	0.25	0.008	0.009					
K	0.10	0.25	0.004	0.009					
M	0 °	7°	0°	7°					
Р	5.80	6.20	0.229	0.244					
R	0.25	0.50	0.010	0.019					

Notes

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